

Europe's leading Reliability and Qualification Facility

Cost effective, Full Turn-Key solutions for the Reliability testing and Qualification of semiconductor devices and electronic modules.

Planning and Development:

- Qualification Planning
- Biased Life Test strategy development
- Life Test Hardware design & manufacture

Qualification Testing:

- High Temperature Operating Life (HTOL)
- High Power HTOL <60W/DUT</p>
- Early Life Failure Rate (ELFR)
- Temperature Humidity Bias (THB)
- Highly Accelerated Stress Test (Biased HAST), UHAST (Unbiased HAST)
- Low Temperature Operating Life (LTOL)
- Temperature Cycling (TC)
- High Temperature Storage (HTS)
- Test Programme Development
- ATE Functional Test (Read Point Test)
- ♦ JEDEC JESD47 Compliant
- ♦ ISO/IEC17025:2005 Accreditation

Board Level Reliability:

- HALT Highly Accelerated Life Test
- HALT Consultancy and training
- Multi Axis Vibration
- Raid Temperature Cycling

Failure Analysis Services:

- Xray package analysis
- CSAM package analysis
- Decapsulation
- FIB/SEM internal inspection
- FIB sectioning and imaging
- SEM EDS studies



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